

| Ref # | Hits    | Search Query  | DBs   | Default Operator | Plurals | Time Stamp       |
|-------|---------|---|---|------------------|---------|------------------|
| L1    | 1099056 | (wafer\$1 or semicondudor\$1 or chip\$1 or substrat\$1 or IC or intergrated adj circuit or PCB or printed adj circuit adj board or PWB or printed adj wiring) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR               | ON      | 2005/12/28 13:06 |
| L2    | 2       | L1 and (detect\$3 or determine)same(defect or flaw or fault or reject\$3)with microfabricat\$2 near3 structures   | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR               | ON      | 2005/12/28 13:10 |
| L3    | 43      | L1 and (detect\$3 or determine)same(defect or flaw or fault or reject\$3)with(repetitive or non adj repetitive)same(area or regions)                          | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR               | ON      | 2005/12/28 13:12 |
| L4    | 26      | L3 and @ad<"20011024"   | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR               | ON      | 2005/12/28 13:13 |
| L5    | 43      | L1 and (detect\$3 or determine)same(defect or flaw or fault or reject\$3)with repetitive same(area or regions)  | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR               | ON      | 2005/12/28 13:12 |
| L6    | 26      | L5 and @ad<"20011024"   | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR               | ON      | 2005/12/28 13:13 |
| L7    | 0       | L6 and creat\$3 same (1D or one adj dimensional\$1 or 1-D)same(cell or array or matrix)   | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR               | ON      | 2005/12/28 13:17 |
| L8    | 0       | L6 and creat\$3 same (1D or one adj dimensional\$1 or 1-D)same(cell or array or matrix)same(contrast or threshold or brightness)with histogram                | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR               | ON      | 2005/12/28 13:19 |

| Ref # | Hits   | Search Query   | DBs   | Default Operator | Plurals | Time Stamp       |
|-------|--------|--|-------|------------------|---------|------------------|
| L1    | 314623 | (wafer\$1 or semicondudor\$1 or chip\$1 or substrat\$1 or IC or intergrated adj circuit or PCB or printed adj circuit adj board or PWB or printed adj wiring or microfabricat\$3 near3 structures) | USPAT | OR               | ON      | 2005/12/28 14:27 |
| L2    | 14     | L1 and (detect\$3 or determine)same(defect or flaw or fault or reject\$3)with(repetitive or non adj repetitive)same(area or regions)and coordinat\$4   | USPAT | OR               | ON      | 2005/12/28 15:46 |
| L3    | 1801   | L1 and creat\$3 and (1D or one adj dimensional\$1 or 1-D)same(cell or array or matrix)   | USPAT | OR               | ON      | 2005/12/28 15:09 |
| L4    | 192    | L3 and creat\$3 and (1D or one adj dimensional\$1 or 1-D)same(cell or array or matrix)same(contrast or brightness or intensity or threshold)   | USPAT | OR               | ON      | 2005/12/28 15:11 |
| L5    | 7      | L3 and creat\$3 and (1D or one adj dimensional\$1 or 1-D)same(cell or array or matrix)same(contrast or brightness or intensity or threshold)same (histogram or profile)                            | USPAT | OR               | ON      | 2005/12/28 15:53 |
| L6    | 4508   | 382/145,141,149,168,274,254,232, 151,286.ccls.   | USPAT | OR               | ON      | 2005/12/28 15:44 |
| L7    | 0      | L5 and (detect\$3 or determine)same(defect or flaw or fault or reject\$3)with(repetitive or non adj repetitive)same(area or regions)and coordinat\$4   | USPAT | OR               | ON      | 2005/12/28 15:45 |
| L8    | 0      | L4 and (detect\$3 or determine)same(defect or flaw or fault or reject\$3)with(repetitive or non adj repetitive)same(area or regions)and coordinat\$4   | USPAT | OR               | ON      | 2005/12/28 15:45 |
| L9    | 8      | L4 and (detect\$3 or determine)and(defect or flaw or fault or reject\$3)and(repetitive or non adj repetitive)and(area or regions)and coordinat\$4  | USPAT | OR               | ON      | 2005/12/28 15:49 |
| L10   | 0      | L6 and L9  | USPAT | OR               | ON      | 2005/12/28 15:47 |
| L11   | 0      | 356/388,394,429,237.2,237.5,237.5, "237".4.ccls.   | USPAT | OR               | ON      | 2005/12/28 15:48 |
| L12   | 2235   | 356/388,394,429,237.2,237.5,237.5, 237.4.ccls.   | USPAT | OR               | ON      | 2005/12/28 15:48 |
| L13   | 4      | L4 and L12   | USPAT | OR               | ON      | 2005/12/28 15:54 |
| L14   | 4      | L4 and L6  | USPAT | OR               | ON      | 2005/12/28 15:50 |
| L15   | 0      | L14 and L5   | USPAT | OR               | ON      | 2005/12/28 15:59 |

|     |      |                                   |       |    |    |                  |
|-----|------|-----------------------------------|-------|----|----|------------------|
| L16 | 7    | L4 and L5                         | USPAT | OR | ON | 2005/12/28 15:51 |
| L17 | 0    | L12 and L5                        | USPAT | OR | ON | 2005/12/28 15:53 |
| L18 | 592  | 250/559.22,559.45.ccis.           | USPAT | OR | ON | 2005/12/28 15:54 |
| L19 | 0    | L4 and L18                        | USPAT | OR | ON | 2005/12/28 15:54 |
| L20 | 0    | 257/184,E21.525,E21.553.ccis      | USPAT | OR | ON | 2005/12/28 15:56 |
| L21 | 559  | 257/184.ccis.                     | USPAT | OR | ON | 2005/12/28 15:56 |
| L22 | 0    | 257/184,E21.525,E21.53.ccis       | USPAT | OR | ON | 2005/12/28 15:56 |
| L23 | 0    | 257/184,21.525,21.53.ccis         | USPAT | OR | ON | 2005/12/28 15:57 |
| L24 | 0    | 257/184,E "21.525,E" "21.53.ccis" | USPAT | OR | ON | 2005/12/28 15:58 |
| L26 | 1955 | 257/184,E21.525,E21.53.ccis.      | USPAT | OR | ON | 2005/12/28 15:58 |
| L27 | 1    | L4 and L26                        | USPAT | OR | ON | 2005/12/28 16:00 |
| L28 | 0    | L27 and L5                        | USPAT | OR | ON | 2005/12/28 15:59 |
| L29 | 1    | L27 and @ad<"20011024"            | USPAT | OR | ON | 2005/12/28 16:00 |

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|-------|------|---|----------|------------------|---------|------------------|
| L1    | 272  | (wafer\$1 or semicondudor\$I or chip\$I or substrat\$I or IC or intergrated adj circuit or PCB or printed adj circuit adj board or PWB or printed adj wiring or microfabricat\$3 near3 structures)and creat\$3 and(1D or one adj dimensional\$1 or 1-D)and(cell or array or matrix)and(contrast or brightness or intensity or threshold)and (histogram or profile).clm.   | US-PGPUB | OR               | ON      | 2005/12/28 16:12 |
| L2    | 3    | (wafer\$1 or semicondudor\$I or chip\$I or substrat\$I or IC or intergrated adj circuit or PCB or printed adj circuit adj board or PWB or printed adj wiring or microfabricat\$3 near3 structures)and creat\$3 and(1D or one adj dimensional\$1 or 1-D)and(cell or array or matrix)and(contrast or brightness or intensity or threshold)and(histogram or profile)and(repetitive or non adj repetitive)same(areas or regions).clm. | US-PGPUB | OR               | ON      | 2005/12/28 16:14 |
| L3    | 0    | L2 and @ad<"20011024"   | US-PGPUB | OR               | ON      | 2005/12/28 16:15 |